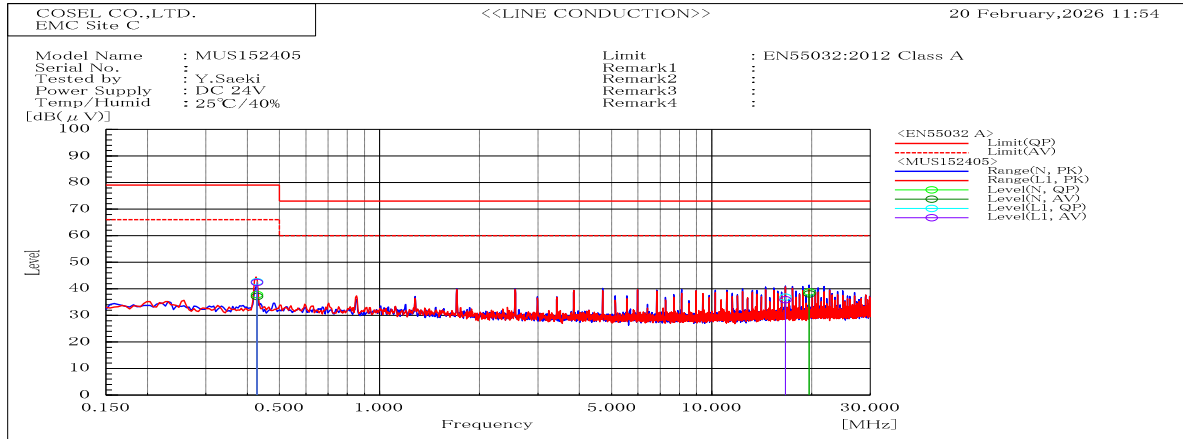
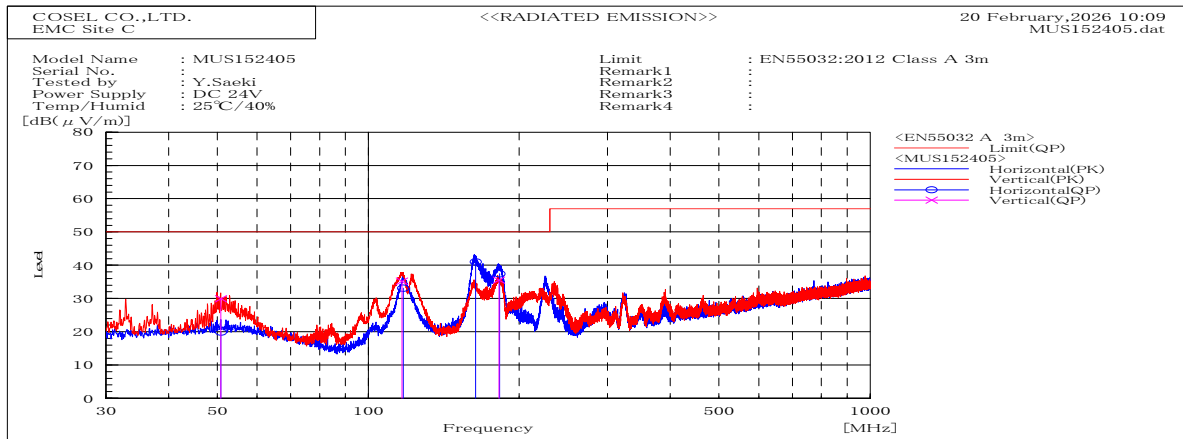


DATA SHEET		Date	15-May-26
Model	MUS152405	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	Y.Saeki



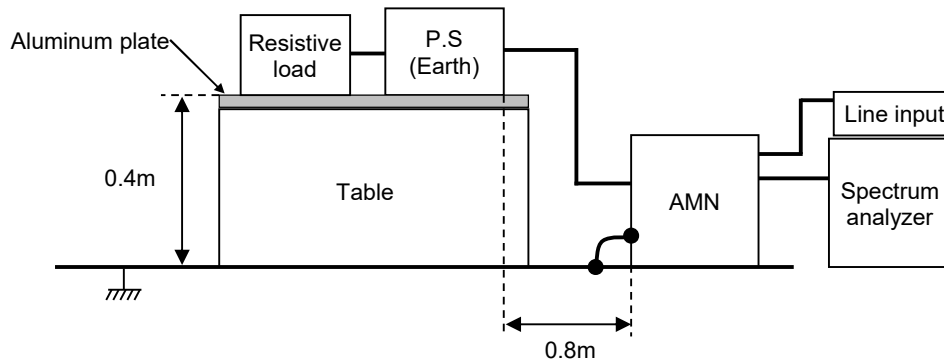
Frequency MHz	Line	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
0.427	N	37.8	37.2	79	66	41.2	28.8	Pass	
19.668	N	38.9	38.1	73	60	34.1	21.9	Pass	
0.427	L1	42.8	42.4	79	66	36.2	23.6	Pass	
16.674	L1	36.9	35.9	73	60	36.1	24.1	Pass	



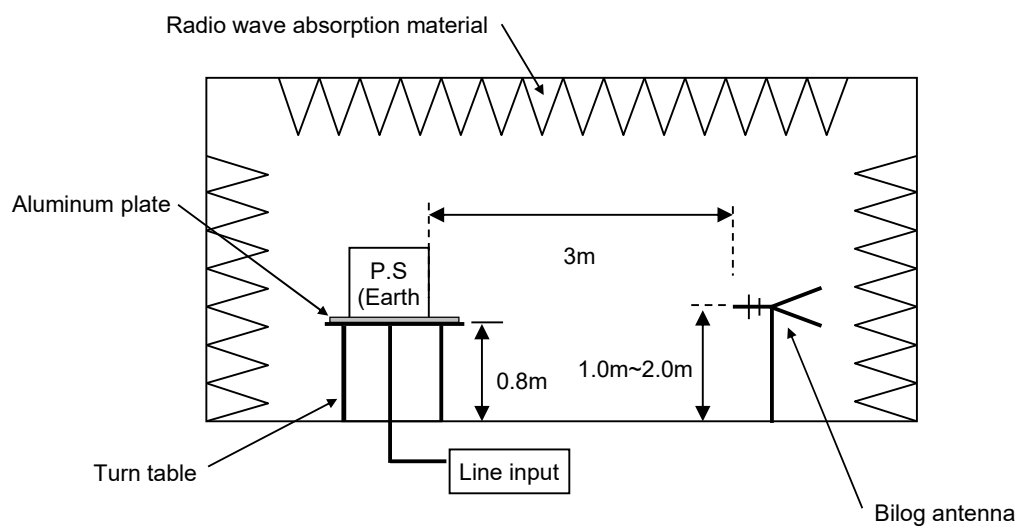
Frequency MHz	Polarization	Stability	Level dB(μV/m)		Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	QP					
50.868	H	Stable	19.9	50	30.1	Pass	108.9	70.6	
117.337	H	Stable	33.1	50	16.9	Pass	165.5	0	
163.653	H	Stable	41	50	9	Pass	179.7	184.7	
182.616	H	Stable	37.4	50	12.6	Pass	198.4	0	
50.852	V	Stable	30	50	20	Pass	100.2	17.3	
116.656	V	Stable	35.2	50	14.8	Pass	118.3	0	
182.083	V	Stable	35.5	50	14.5	Pass	100.2	294.6	

DATA SHEET		Date	15-May-26
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	Y.Saeki

1. Line conduction



2. Radiated emission



Conditions

Test : EMI
Model Name: MUS15□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

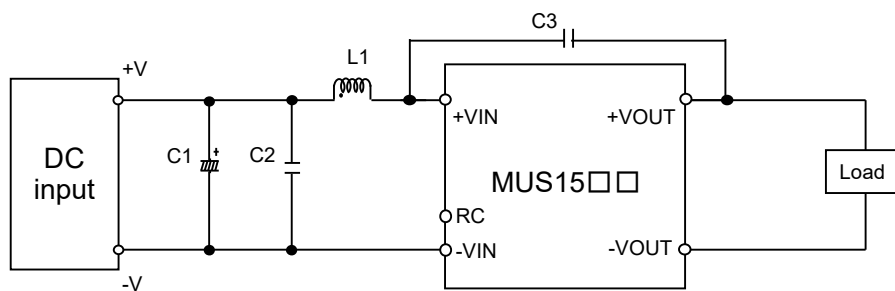


Fig.1 MUS15□□ Testing circuitry

C1 :	MUS1524□	50V 47 μ F Electric capacitor (UPWseries NICHICON)
	MUS1548□	-
C2 :	MUS1524□	50V 4.7 μ F Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
	MUS1548□	100V 2.2 μ F Ceramic capacitor (C3216X7S2A225KT TDK)
C3 :	MUS15□□	2000V 1000pF Ceramic capacitor (C3225X7S3D102K200AA TDK)
L1 :	MUS1524□	1600mA 22 μ H Inductor (LQH5BPN220M38 MURATA MANUFACTURING)
	MUS1548□	1100mA 47 μ H Inductor (LQH5BPN470M38 MURATA MANUFACTURING)